

FORM PTO-1449	SERIAL NO. Not yet assigned	CASE NO. 10808/227
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE Herewith	GROUP ART UNIT Not yet assigned
(use several sheets if necessary)	APPLICANT(S): Ronald Kakoschke	

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
	A1	US2002/0130354 A1	September 19, 2002	Sekigawa et al.		
	A2	<del>6,368,108 B1</del>	May 28, 2002	Krivokapic et al.	6,396,108	
	A3	5,930,605	July 27, 1999	Mistry et al.		
	A4	<del>5,693,918</del>	November 4, 1997	Smith et al.	5,683,918	
	A5	4,996,574	February 26, 1991	Shirasaki		
	A6	4,965,213	October 23, 1990	Blake		

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO

## OTHER ART - NON PATENT LITERATURE DOCUMENTS

(Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.

EXAMINER INITIAL	A7	J.M. Hwang, H. Lu, Y.D. Sheu, W. Bailey, P. Mei, G. Pollack, <i>Premature Breakdown in Non-Fully Depleted SOI/Mosfets with Body-Tied-To-Source Structure</i> , pgs. 34-35, SOI Conference, Proceedings. IEEE, October 1, 1991.
	A8	C.J. Chang-Hasnain, J.P. Harbison, C.E. Zah, L.T. Florez and N.C. Andreiadakis, <i>Suppression of Latch in SOI Mosfets By Silicidation of Source</i> , pgs. 1003-1005, Electronics Letters, Vol. 27, May 23, 1991.
	A9	F.L. Duan and D.E. Ioannou, <i>Design and Analysis of a Novel Mixed Accumulations/Inversion Mode FD SOI Mosfet</i> , pgs. 100-101, Proceedings IEEE International SOI Conference, October 1997.
	A10	S. Cristoloveanu and G. Reichert, <i>Recent Advances in SOI Materials and Device Technologies for High Temperature</i> , pgs. 86-93, High-Temperature Electronics, Materials, Devices and Sensors Conference, IEEE, February 1998.
	A11	Srinath Krishnan, <i>Efficacy of Body Ties Under Dynamic Switching Conditions in Partially Depleted SOI CMOS Technology</i> , pgs. 140-141, IEEE International SOI Conference, 1997.
	A12	Jeffrey W. Sleight, <i>DC and Transient Characterization a Compact Schottky Body Contact Technology for SOI Transistors</i> , pgs. 1451-1456, IEEE Transactions on Electron Devices, July, 1999.
	A13	Copy of International Search Report from corresponding PCT application number PCT/DE03/03131.
	A14	Copy of Examination Report from corresponding PCT application number PCT/DE03/03131.

EXAMINER /Sarah Salerno/	DATE CONSIDERED 11/05/2007
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /S.K.S./